

<b>Search Notes</b>		
	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/594,500	IWASAKI, MITSUTAKA
	<b>Examiner</b>	<b>Art Unit</b>
	shih-wen hsieh	2861

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner